

Products and Technologies for Advanced Wafer Processing

Drive Innovation, Deliver Excellence

ASM International
Analyst and Investor Technology Seminar
Semicon West July 11 2012



ASM Front-end Products and selected applications

- ALD High-k gate/metal gate
- PEALD for Spacer Defined Double Patterning
- Epitaxy
- Low-k
- Vertical Furnace
- Platform roadmap
- Summary

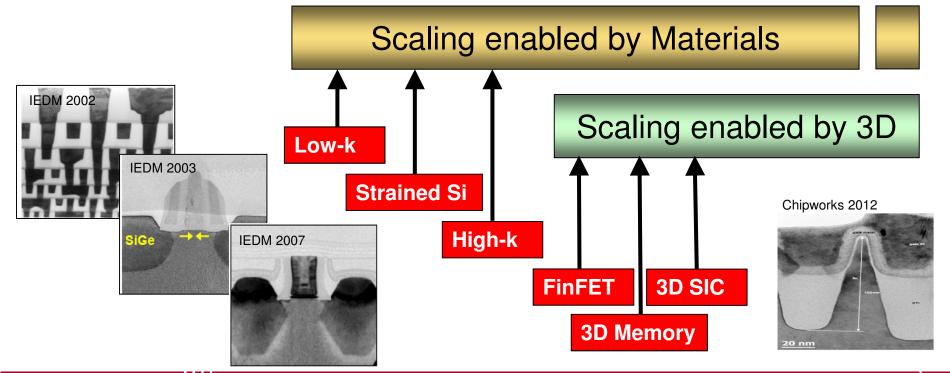


Scaling will increasingly be enabled by New Materials and 3D Technologies

1990 1995 2000 2005 2010 2015 2020 2025

Scaling enabled by Litho







Market Requirements: 32nm→22nm →14nm and beyond

Process

ALD and PEALD

- ALD solution (Hafnium oxide)
- PEALD Low temp dielectrics

Diffusion Furnace

- · Advanced batch processing
- Unique "dual reactor dual boat" design

Epitaxy

- Epitaxial films for analog devices
- Epitaxial films for NMOS/PMOS
 PECVD
- · Extreme low-k films

Application

- ALD key for High-k Metal Gate technology
- 3D FinFET requires more conformal layers, strength of ALD
- · SDDP-application of PE-ALD
- Smallest footprint per reactor
- · Lowest Cost of Ownership
- Affordable method of high quality crystal growth
- Thick Epi layers for power devices
- Strained Epi films for CMOS
- Advanced intermetal dielectric film

ASM Relative Positioning

- √ #1 in the served ALD market
- ✓ Qualified by nearly all Logic manufacturers
- ✓ Strengthening inroads into Memory with PEALD
- ✓ Leading IC manufacturers are customers

- ✓ ASM one of only two top vendors
- ✓ ASM one of only three top vendors in PE-CVD



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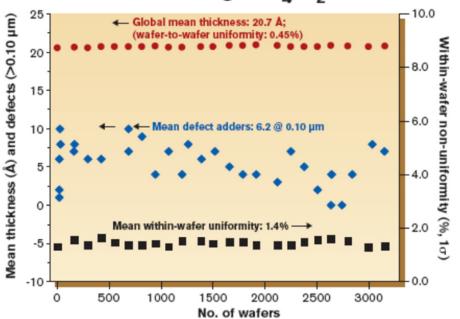
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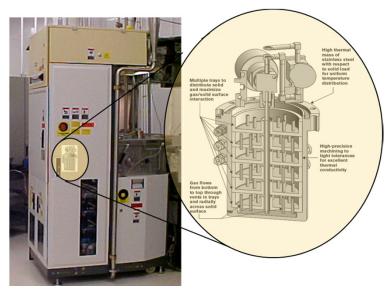


High-k Metal Gate: Gate Dielectric

Marathon Data Using HfCl₄/H₂O Process



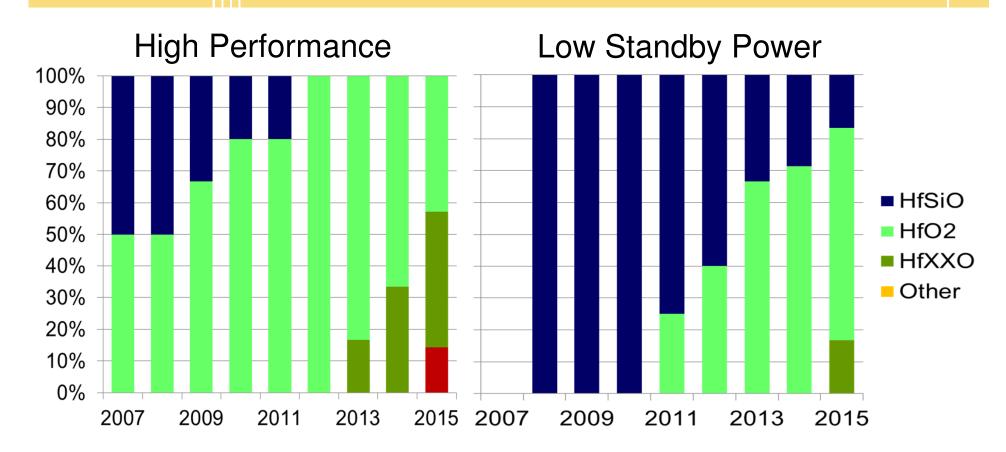
Pulsar 3000 with solid source



- Current practice: Hf based (HfO₂ or HfSiO₄) from HfCl₄/SiCl₄/H₂O
 - So far, MO chemistries have proven to be inferior (roughness, leakage, reliability)
- Migration towards HfO₂ as the standard because lower Equivalent Oxide Thicknesses (EOT) can be reached
 - EOT's in the range of 0.7-1.2nm demonstrated with HfO2



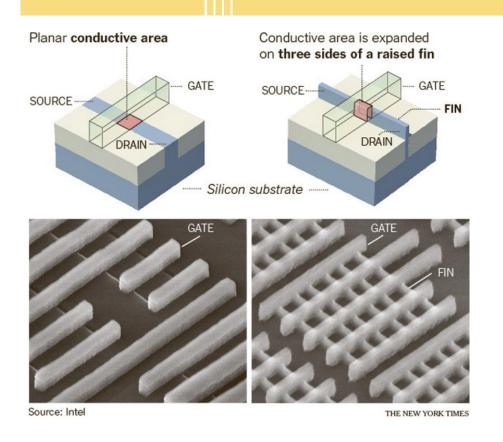
High-k Material Adoption Trend High Performance and Low Standby Power

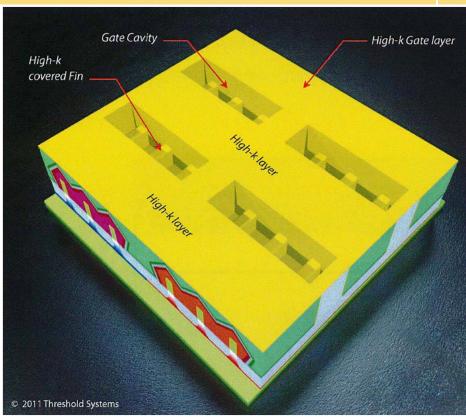


- ALD HfO₂ is the only material for HP devices
- High-k for LSTP devices will transition to ALD HfO₂
- Convergence to gate last process for all logic to enable optimization of work function



Transition to 3D Fully Depleted Devices and the Importance of Conformality



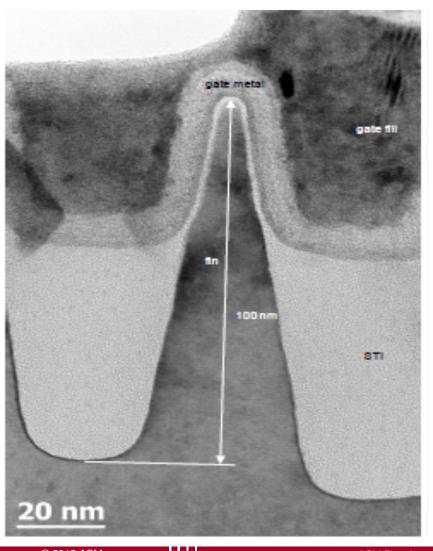


- Metal and high-k over very challenging topography
- EOT and work function have to be uniform over fin height
- FinFET's drive need for conformal films with uniform thickness, composition and micro-structure



Intel FinFET (Chipworks, May 2012)

Perpendicular to Fin



- Metal and high-k over very challenging topography
- EOT and work function have to be uniform over fin height
- Success of FinFETs is enabled with ALD metal gates
- Entire spectrum of work functions researched and available from ASM





- ALD HfO₂ has become the de-facto high-k standard
- Gate last process will be used for logic to enable work function optimization of the metal gate electrodes
- 3D FinFET's drive adoption of ALD, not only for the dielectric, but now also for metals
- Metals and damascene like process flows have penetrated the Front-end of the Line



ASM Front-end Products ALD

Front-End Operations

Pulsar® XP

- ALD for high-k
- Cross-flow reactor
- Solid source delivery system

EmerALD® XP

- ALD for metal gates
- Showerhead reactor





EmerALD® XP



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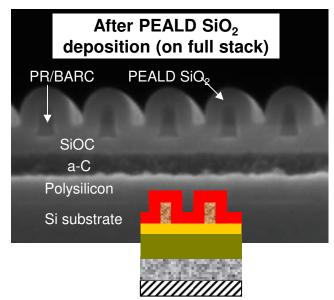
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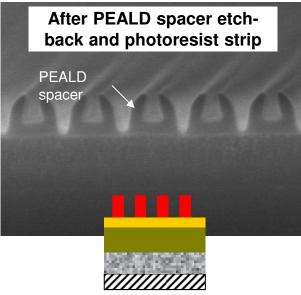
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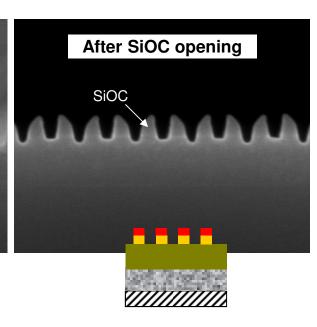
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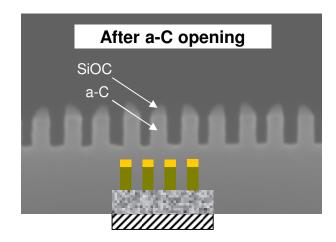


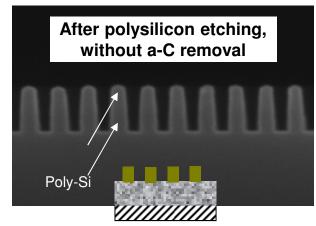
LT PEALD SiO Spacer Defined Double Patterning

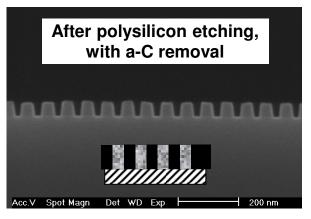






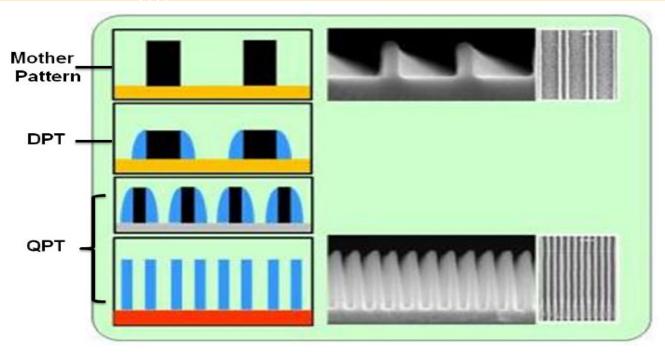








Spacer Defined Multiple Patterning



K. Kim et al, Samsung, SPIE advanced lithography 2012

Spacer defined quadruple patterning : two sequences of spacer pattern transfer



ASM Front-end Products PEALD

MIR 3000

- PEALD of SiO₂ for Spacer Defined Double Patterning
- High productivity XP cluster with 2 PEALD modules, each processing 4 wafers
- PEALD enables tunable SiO₂ film properties, to optimize for film quality or ease of film removal



MIR 3000



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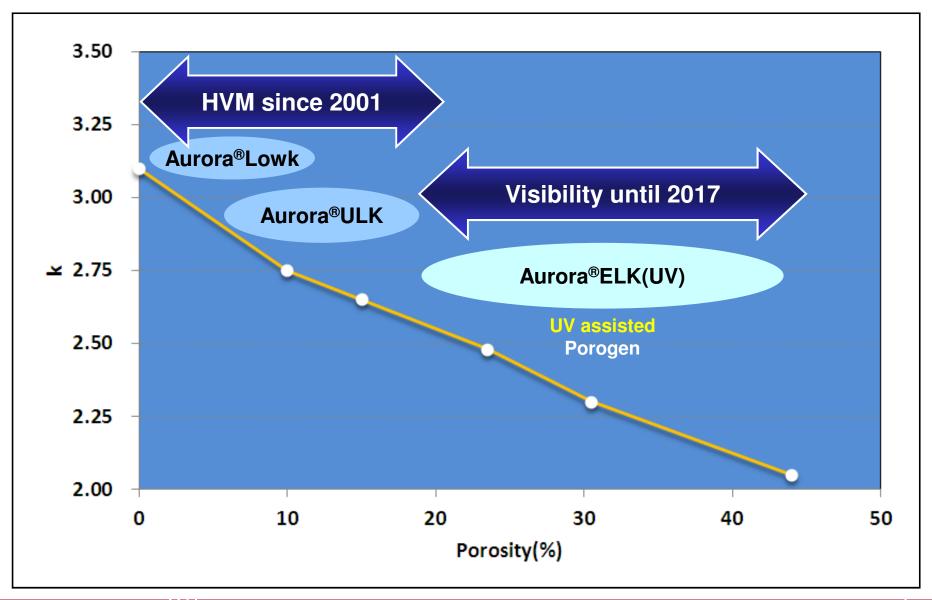
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Extendibility of ASM's Low-k Solution





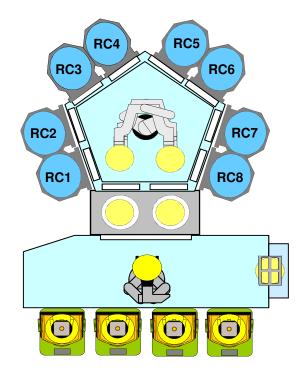
ASM Front-end Products PEALD and PECVD

Front-End Operation

Introduced during Semicon West 2012

XP8

- High productivity single wafer tool for both PEALD and PECVD applications
- Accommodates up to 8 chambers for PEALD or PECVD
- PEALD and PECVD can be integrated on the same platform





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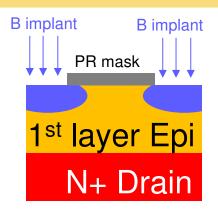
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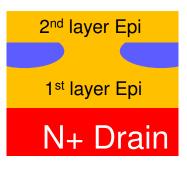
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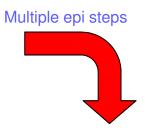


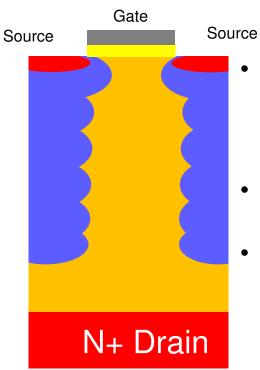
Epi layers for Power Devices Multi-Layer Epi Technology



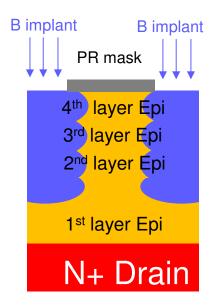








- Number of epi layers dependent upon the breakdown voltage required (i.e. product application specific)
- Typical breakdown voltages from 600 – 800V
- Implemented in production by various companies



ASM Product: Epsilon® 3200

Epi for advanced power devices



ASM Front-end Products Epitaxy

Introduced during Semicon West 2012

- Intrepid® XP
 - Epi for advanced CMOS strain
 - High productivity system using ASM's XP cluster with 4 Epi reactors
 - Integrated Pre-Clean for pre-Epi interface control



Intrepid™ XP



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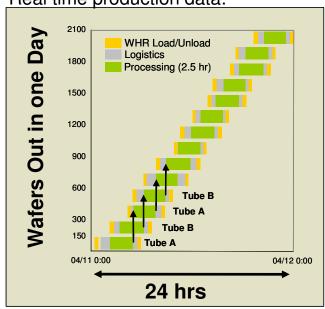


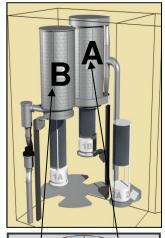
A412 PLUS: Productivity and Innovation

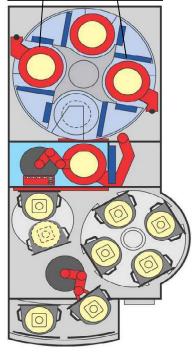
Productivity

- One A412 PLUS = up to 80 kwpm (2.5 hr process, 95% available, 150 wafer boat)
- About 40% lower capex per m² as competitors
- Dual boat/dual reactor system

Real time production data:

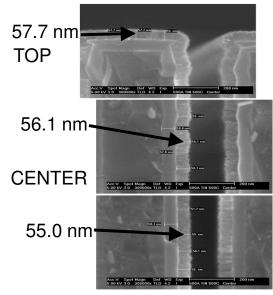


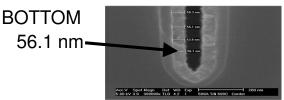




Innovation

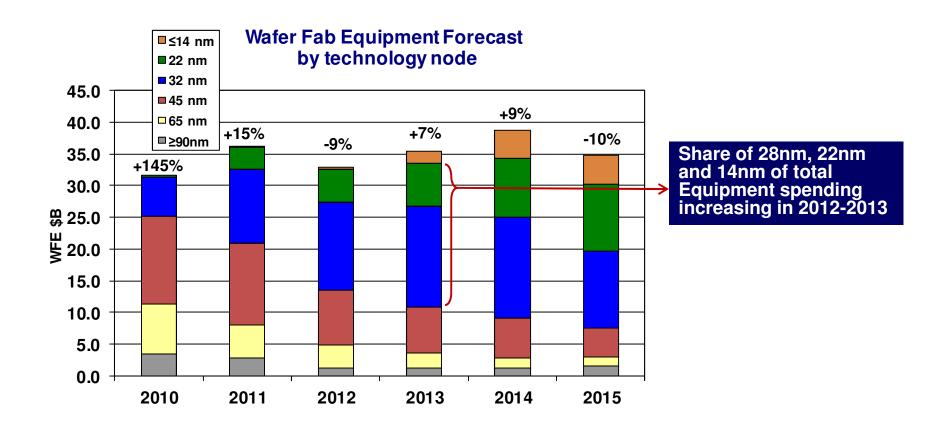
- Addition of ALD processes
- Example: Batch ALD TiN process







Wafer Fab Equipment Forecast



Key customer ALD penetrations in 28 and 22nm: market segments with high expected growth



- Adoption of more ALD and PEALD applications in HVM continues
 - #1 position in ALD for High-k gate
 - 3D FinFET's drive adoption of ALD, not only for the dielectric, but also for metals
 - strong inroads into patterning applications with PEALD
- Introduced Intrepid[®] XP, system with 4 Epi reactors, for CMOS strain Epi
- Introduced XP8, high productivity system for PEALD and PECVD applications
- ASM's Vertical Furnace is providing the lowest CoO and footprint per reactor
- 450mm development started and first tools have been shipped

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